

From the Editor

MT-10 Awards



In the July issue of this magazine, I promised to provide details about the MT-10 Awards. These new awards, to be sponsored by *Microscopy Today*, will recognize the best new products and methods across the entire field of microscopy. Since our field is broad, it seems appropriate to have ten awards per year—five primarily related to the life sciences and five related to the physical sciences. In each of these areas, there may be interesting new developments in light microscopy, scanning probe microscopy, electron microscopy, ion microscopy, acoustic microscopy, microanalysis, specimen preparation, etc. These awards will honor the best developments in microscopy from the previous calendar year.

The procedure for nominating a particular device or method for an MT-10 Award is as follows. A letter of intent to nominate must be sent by December 15 to the *Microscopy Today* Editor-in-Chief via the “MT-10 Award Nomination” box at the magazine website: www.microscopy-today.com. Nominators must then submit full nomination applications to the same website by March 1. Nominations can come from employers, colleagues, or self-nominations. Nominations will only be accepted for the following: commercial microscopy-related products that were first marketed in the previous year or new microscopy methods and inventions that were published in peer-reviewed journals in the previous year. The nomination form requires information about the inventor or author, the product or method name, the date of commercial product release or date of publication, what the product or method does, how the product or method works, what theories are involved, why the product or method is an advance over previous technologies, a description of the significance of the development for science and technology, and what are likely to be the principal applications of the product or method. For the first year of these awards, there will be no entry fee.

Winning products and methods will be selected on the basis of their importance and usefulness to the microscopy community. Three-time R&D 100 Award-winner Tom Kelly will lead a panel of judges, representing various sub-fields of microscopy and microanalysis, to select the winners. Winners will be notified by May 15 and honored at the summer Microscopy & Microanalysis 2010 meeting to be held in Portland, Oregon. Descriptions of the winning products and methods will be published in the print and digital editions of the September 2010 issue of *Microscopy Today*.

Charles Lyman
Editor-in-Chief

Publication Objective: to provide information of interest to microscopists.

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Editorial Staff

Charles E. Lyman
Editor-in-Chief
charles.lyman@lehigh.edu
(610) 758-4249

Gennifer Levey, *Production Manager*
gleyev@meridianartproduction.com
(212) 780-0315

Ron Anderson, *Executive Editor*
microscopytoday@tampabay.rr.com

Phil Oshel, *Technical Editor*
oshel1pe@cmich.edu

Stephen Carmichael, *Columnist*
carmichael.stephen@mayo.edu

Michael Davidson, *Pioneers Editor*
davidson@magnet.fsu.edu

Steven Barlow, *Education Editor*
sbarlow@sunstroke.sdsu.edu

Thomas E. Phillips, *Consulting Editor*
phillipst@missouri.edu

E. Ann Ellis, *Microscopy 101 Editor*
eann.ellis@worldnet.att.net

John Shields, *Humor Editor*
jshields@cb.uga.edu

Advertising Sales

M.J. Mrvica Associates, Inc.
2 West Taunton Avenue, Berlin, NJ 08009
mjmrsvica@mrvica.com
(856) 768-9360

Amy Reuter, *Account Manager*
areuter@mrvica.com

Magazine website:

<http://www.microscopy-today.com>

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New York, NY 10013-2473
(212) 337-5000

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